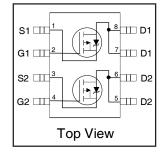
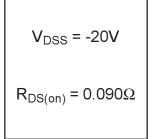
# International Rectifier

#### **HEXFET® Power MOSFET**

- Generation V Technology
- Ultra Low On-Resistance
- Dual P-Channel Mosfet
- Surface Mount
- Available in Tape & Reel
- Dynamic dv/dt Rating
- Fast Switching
- Lead-Free

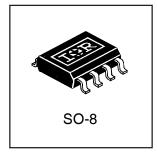
#### Description





Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The SO-8 has been modified through a customized leadframe for enhanced thermal characteristics and multiple-die capability making it ideal in a variety of power applications. With these improvements, multiple devices can be used in an application with dramatically reduced board space. The package is designed for vapor phase, infra red, or wave soldering techniques. Power dissipation of greater than 0.8W is possible in a typical PCB mount application.



#### **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>A</sub> = 25°C	10 Sec. Pulsed Drain Current, V <sub>GS</sub> @ -4.5V	-4.7	
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ -4.5V	-4.3	
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ -4.5V	-3.4	Α
I <sub>DM</sub>	Pulsed Drain Current ①	-17	
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation	2.0	W
	Linear Derating Factor	0.016	W/°C
$V_{GS}$	Gate-to-Source Voltage	±12	V
dv/dt	Peak Diode Recovery dv/dt ②	-5.0	V/ns
$T_{J,}T_{STG}$	Junction and Storage Temperature Range	-55 to + 150	°C

#### Thermal Resistance Ratings

	Parameter	Тур.	Max.	Units
$R_{\theta JA}$	Maximum Junction-to-Ambient⊕		62.5	°C/W

# Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	-20			V	V <sub>GS</sub> = 0V, ID = -250µA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.012		V/°C	Reference to 25°C, I <sub>D</sub> = -1mA
D	Otatia Dusin ta Osama On Desistana			0.090	Ω	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -2.2A ③
R <sub>DS(ON)</sub>	Static Drain-to-Source On-Resistance			0.140	52	V <sub>GS</sub> = -2.7V, I <sub>D</sub> = -1.8A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	-0.70			V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
g <sub>fs</sub>	Forward Transconductance	4.0			S	$V_{DS} = -16V, I_{D} = -2.2A$
	B : 4 0 4			-1.0		V <sub>DS</sub> = -16V, V <sub>GS</sub> = 0V
IDSS	Drain-to-Source Leakage Current			-25	μA	V <sub>DS</sub> = -16V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
lass	Gate-to-Source Forward Leakage			-100	nΑ	V <sub>GS</sub> = -12V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			100	IIA	V <sub>GS</sub> = 12V
Qg	Total Gate Charge			22		I <sub>D</sub> = -2.2A
Q <sub>gs</sub>	Gate-to-Source Charge			3.3	nC	V <sub>DS</sub> = -16V
$Q_{gd}$	Gate-to-Drain ("Miller") Charge			9.0		$V_{GS}$ = -4.5V, See Fig. 6 and 12 ③
t <sub>d(on)</sub>	Turn-On Delay Time		8.4			V <sub>DD</sub> = -10V
t <sub>r</sub>	Rise Time		26			$I_D = -2.2A$
t <sub>d(off)</sub>	Turn-Off Delay Time		51		ns	$R_G = 6.0\Omega$
t <sub>f</sub>	Fall Time		33			$R_D$ = 4.5 $\Omega$ , See Fig. 10 $\Im$
L <sub>D</sub>	Internal Drain Inductance		4.0		nH	Between lead tip
L <sub>S</sub>	Internal Source Inductance		6.0			and center of die contact
C <sub>iss</sub>	Input Capacitance		610			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance		310		pF	$V_{DS} = -15V$
C <sub>rss</sub>	Reverse Transfer Capacitance		170			f = 1.0MHz, See Fig. 5

### Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
ls	Continuous Source Current			2.5		MOSFET symbol
	(Body Diode)	1-1-1-	-2.5	Α	showing the	
I <sub>SM</sub>	Pulsed Source Current		47		integral reverse	
	(Body Diode) ①			-17		p-n junction diode.
$V_{SD}$	Diode Forward Voltage			-1.0	V	$T_J = 25$ °C, $I_S = -1.8A$ , $V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		56	84	ns	$T_J = 25$ °C, $I_F = -2.2A$
$Q_{rr}$	Reverse RecoveryCharge		71	110	nC	di/dt = 100A/µs ③
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )

 $<sup>\</sup>begin{tabular}{ll} \textcircled{2} & I_{SD} \leq -2.2A, & di/dt \leq -50A/\mu s, & V_{DD} \leq V_{(BR)DSS}, \\ & T_J \leq 150 \ensuremath{^{\circ}C} \ensuremath{^{\circ}} \ensuremath{^{\circ$ 

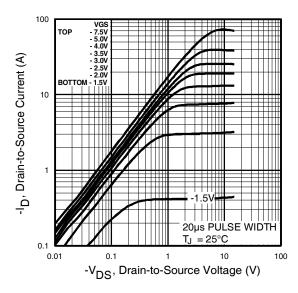


Fig 1. Typical Output Characteristics

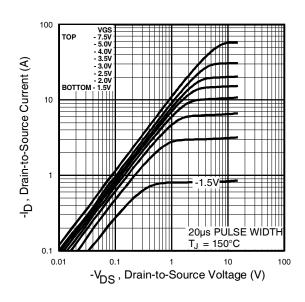


Fig 2. Typical Output Characteristics

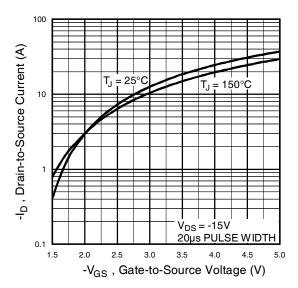
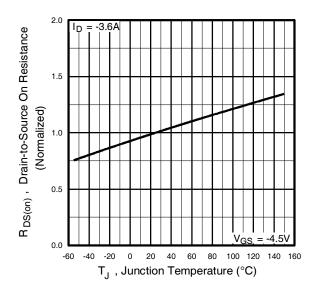
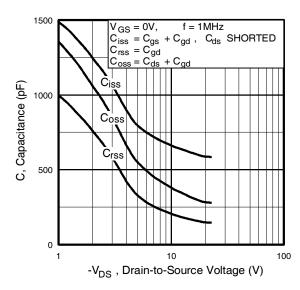


Fig 3. Typical Transfer Characteristics



**Fig 4.** Normalized On-Resistance Vs. Temperature

# IRF7304PbF



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

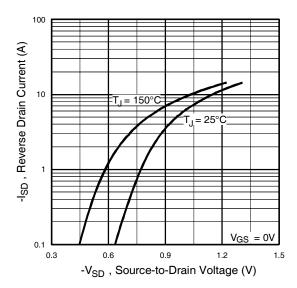
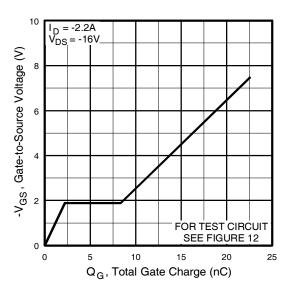


Fig 7. Typical Source-Drain Diode Forward Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

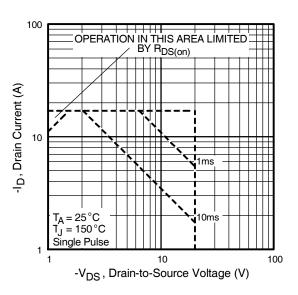


Fig 8. Maximum Safe Operating Area

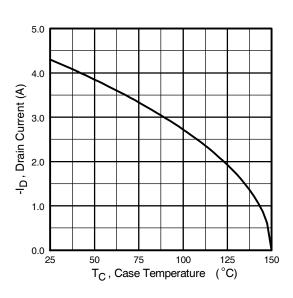


Fig 9. Maximum Drain Current Vs. Ambient Temperature

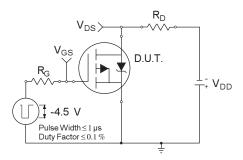


Fig 10a. Switching Time Test Circuit

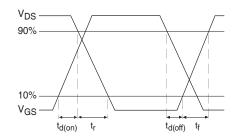


Fig 10b. Switching Time Waveforms

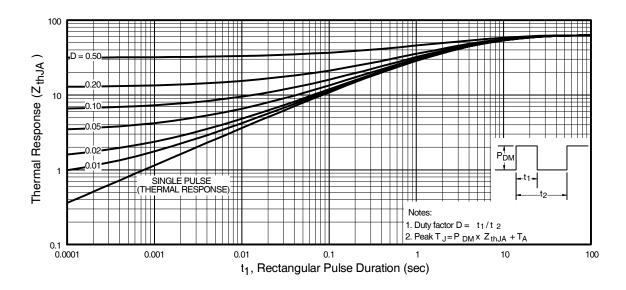


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

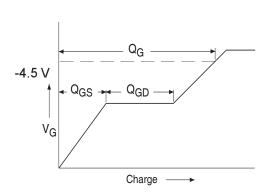


Fig 12a. Basic Gate Charge Waveform

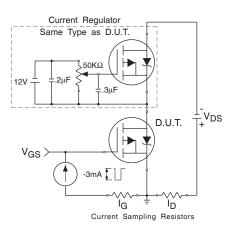
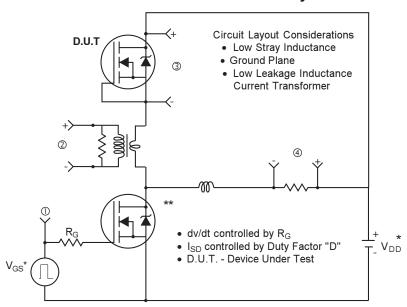
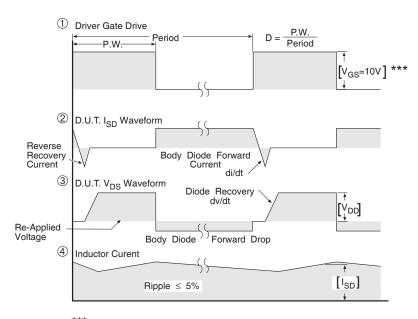


Fig 12b. Gate Charge Test Circuit

# Peak Diode Recovery dv/dt Test Circuit



- \* Reverse Polarity for P-Channel
- \*\* Use P-Channel Driver for P-Channel Measurements



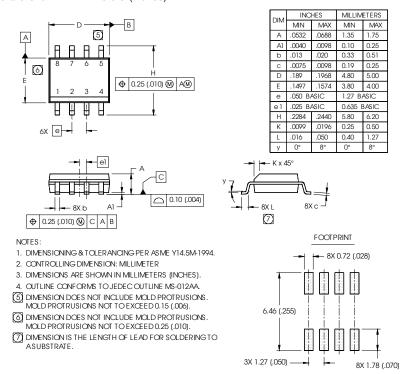
\*\*\*  $V_{GS}$  = 5.0V for Logic Level and 3V Drive Devices

Fig 13. For P-Channel HEXFETS

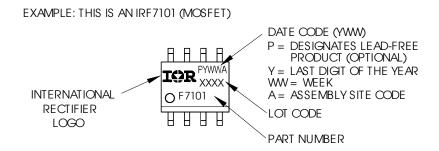
# IRF7304PbF

## SO-8 Package Outline

Dimensions are shown in milimeters (inches)

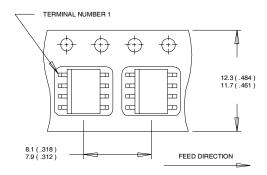


# SO-8 Part Marking Information (Lead-Free)



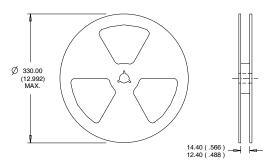
# SO-8 Tape and Reel

Dimensions are shown in milimeters (inches)



#### NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
  2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
  3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



- NOTES:
  1. CONTROLLING DIMENSION: MILLIMETER.
  2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Data and specifications subject to change without notice. This product has been designed and qualified for the Consumer market. Qualifications Standards can be found on IR's Web site.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

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